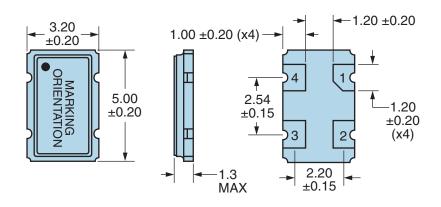


| Nominal Frequency | 48.000MHz |
|---------------------------------------|--|
| Frequency Tolerance/Stability | ±100ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Output Load Change, First Year Aging at 25°, 260°C Reflow, Shock, and Vibration) |
| Aging at 25°C | ±5ppm/Year Maximum |
| Operating Temperature Range | 0°C to +70°C |
| Supply Voltage | 1.8Vdc ±5% |
| Input Current | 4mA Maximum (No Load) |
| Output Voltage Logic High (Voh) | 90% of Vdd Minimum (IOH = -8mA) |
| Output Voltage Logic Low (Vol) | 10% of Vdd Maximum (IOL = +8mA) |
| Rise/Fall Time | 6nSec Maximum (Measured at 20% to 80% of waveform) |
| Duty Cycle | 50 ±10(%) (Measured at 50% of waveform) |
| Load Drive Capability | 15pF Maximum |
| Output Logic Type | CMOS |
| Pin 1 Connection | Tri-State (High Impedance) |
| Tri-State Input Voltage (Vih and Vil) | 90% of Vdd Minimum or No Connect to Enable Output, 10% of Vdd Maximum to Disable Output (High Impedance) |
| Standby Current | 10μA Maximum (Pin 1 = Ground) |
| Absolute Clock Jitter | ±100pSec Maximum |
| Start Up Time | 10mSec Maximum |
| Storage Temperature Range | -55°C to +125°C |

| | NVIRONMENTAL & MECHANICAL SPECIFICATIONS | |
|------------------------------|---|--|
| ESD Susceptibility | MIL-STD-883, Method 3015, Class 1, HBM: 1500V | |
| Fine Leak Test | MIL-STD-883, Method 1014, Condition A | |
| Flammability | UL94-V0 | |
| Gross Leak Test | MIL-STD-883, Method 1014, Condition C | |
| Mechanical Shock | MIL-STD-883, Method 2002, Condition B | |
| Moisture Resistance | MIL-STD-883, Method 1004 | |
| Moisture Sensitivity | J-STD-020, MSL 1 | |
| Resistance to Soldering Heat | MIL-STD-202, Method 210, Condition K | |
| Resistance to Solvents | MIL-STD-202, Method 215 | |
| Solderability | MIL-STD-883, Method 2003 | |
| Temperature Cycling | MIL-STD-883, Method 1010, Condition B | |
| Vibration | MIL-STD-883, Method 2007, Condition A | |

EH3900TS-48.000M TR

MECHANICAL DIMENSIONS (all dimensions in millimeters)



| PIN | CONNECTION |
|------|---|
| 1 | Tri-State |
| 2 | Case Ground |
| 3 | Output |
| 4 | Supply Voltage |
| LINE | MARKING |
| 1 | EPO |
| 2 | XXXXX XXXXX=Ecliptek Manufacturing Identifier |

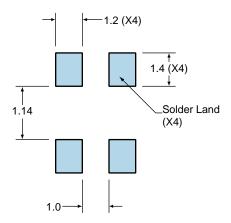
ORPORATION

FCL

K

Suggested Solder Pad Layout

All Dimensions in Millimeters



All Tolerances are ±0.1

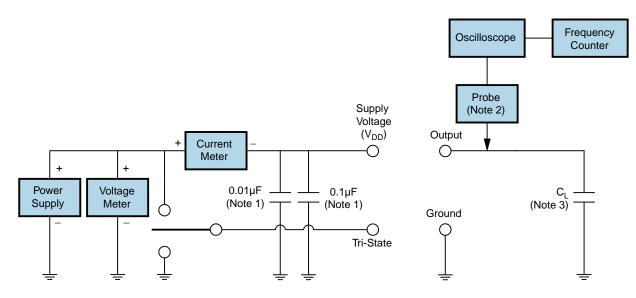
EH3900TS-48.000M TR



OUTPUT WAVEFORM & TIMING DIAGRAM



Test Circuit for CMOS Output



Note 1: An external 0.1μ F low frequency tantalum bypass capacitor in parallel with a 0.01μ F high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

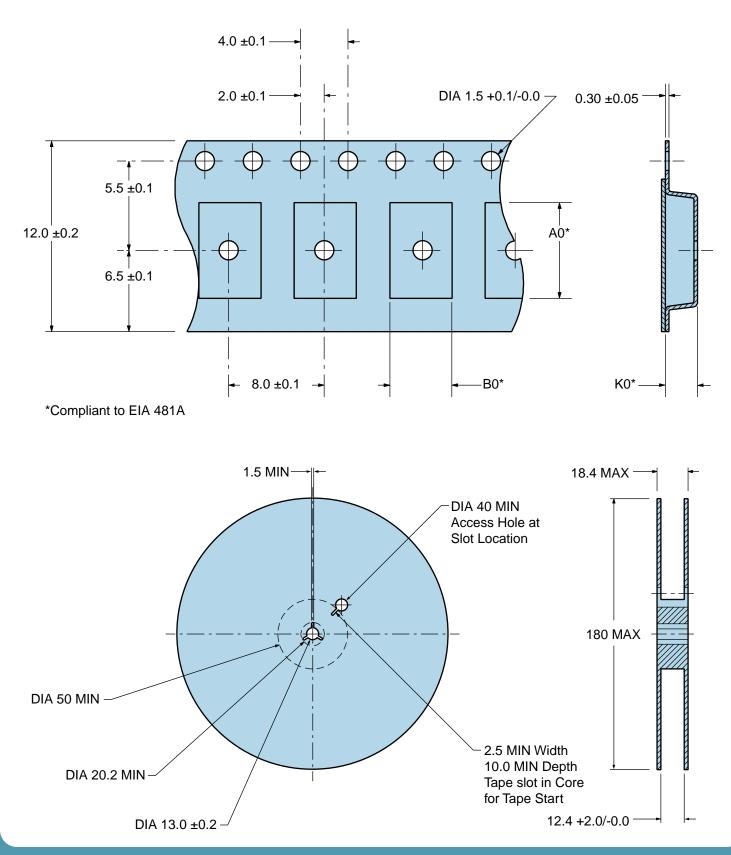
Note 3: Capacitance value C_L includes sum of all probe and fixture capacitance.

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Tape & Reel Dimensions

Quantity Per Reel: 1,000 units



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Recommended Solder Reflow Methods

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High Temperature Infrared/Convection

| T _s MAX to T _L (Ramp-up Rate) | 3°C/second Maximum |
|---|--------------------------------------|
| Preheat | |
| - Temperature Minimum (T _s MIN) | 150°C |
| Temperature Typical (T_s TYP) | 175°C |
| Temperature Maximum (T_s MAX) | 200°C |
| - Time (t _s MIN) | 60 - 180 Seconds |
| Ramp-up Rate (T⊾ to T _P) | 3°C/second Maximum |
| Time Maintained Above: | |
| - Temperature (T∟) | 217°C |
| - Time (t∟) | 60 - 150 Seconds |
| Peak Temperature (T _P) | 260°C Maximum for 10 Seconds Maximum |
| Target Peak Temperature (T _P Target) | 250°C +0/-5°C |
| Time within 5°C of actual peak (t _P) | 20 - 40 seconds |
| Ramp-down Rate | 6°C/second Maximum |
| Time 25°C to Peak Temperature (t) | 8 minutes Maximum |
| Moisture Sensitivity Level | Level 1 |
| | |



Recommended Solder Reflow Methods

EH3900TS-48.000M TR



Low Temperature Infrared/Convection 240°C

| T _s MAX to T _L (Ramp-up Rate) | 5°C/second Maximum |
|---|--|
| Preheat | |
| - Temperature Minimum (T _s MIN) | N/A |
| - Temperature Typical (T _s TYP) | 150°C |
| - Temperature Maximum (T _s MAX) | N/A |
| - Time (t _s MIN) | 60 - 120 Seconds |
| Ramp-up Rate (T⊾ to T _P) | 5°C/second Maximum |
| Time Maintained Above: | |
| - Temperature (T₋) | 150°C |
| - Time (t∟) | 200 Seconds Maximum |
| Peak Temperature (T _P) | 240°C Maximum |
| Target Peak Temperature (T _P Target) | 240°C Maximum 1 Time / 230°C Maximum 2 Times |
| Time within 5°C of actual peak (t _p) | 10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time |
| Ramp-down Rate | 5°C/second Maximum |
| Time 25°C to Peak Temperature (t) | N/A |
| Moisture Sensitivity Level | Level 1 |

Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum.

High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum.